



Thin Solid Films

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Contents

Publication schedule	v
OPTICAL THIN FILMS	
<i>Optically active films and ion processing of optical materials</i>	
Properties of transparent conducting oxides deposited at room temperature	1
L. Davis (Fort Lauderdale, FL, USA)	
Optical switching technology for glazings	6
C. M. Lampert (Berkeley, CA, USA)	
Low temperature preparation of transparent conducting ZnO:Al thin films by chemical beam deposition	14
H. Sato, T. Minami, S. Takata, T. Miyata and M. Ishii (Ishikawa, Japan)	
SnO ₂ transparent conductor films produced by filtered vacuum arc deposition	20
A. Ben-Shalom, L. Kaplan, R. L. Boxman, S. Goldsmith and M. Nathan (Tel-Aviv, Israel)	
Transparent conducting p-type NiO thin films prepared by magnetron sputtering	27
H. Sato, T. Minami, S. Takata and T. Yamada (Ishikawa, Japan)	
Characterization of n-CdS/p-CuGa _x In _{1-x} Se ₂ thin film heterojunctions	32
Y. Aparna, P. S. Reddy, B. Srinivasulu Naidu and P. Jayarama Reddy (Tirupati, India)	
<i>CVD, PECVD and non-vacuum deposition techniques for optical coating</i>	
Low temperature preparation of SrTiO ₃ thin films	37
E. Dayalan and M. S. Tomar (Tulsa, OK, USA)	
Thermal stability of pyrolytic tin oxide films on aluminium	40
A. Roos (Uppsala, Sweden), G. Chinyama (Lusaka, Zambia) and P. Hedenqvist (Uppsala, Sweden)	
Optical properties and equilibrium temperatures of titanium-nitride- and graphite-coated Langmuir probes for space application	46
M. Veszelei and E. Veszelei (Uppsala, Sweden)	
Deposition and characterization of multicomponent oxide films and multilayers from aqueous solution	51
G. J. Exarhos and N. J. Hess (Richland, WA, USA)	
Silicon based, protective transparent multilayer coatings deposited at high rate on optical polymers by dual-mode MW/r.f. PECVD	58
J. C. Rostaing, F. Coeuret (Jouy-en-Josas, France), B. Drevillon, R. Etemadi, C. Godet, J. Huc, J. Y. Parey and V. A. Yakovlev (Palaiseau, France)	
Inhomogeneous dielectrics grown by plasma-enhanced chemical vapor deposition	64
S. Lim, J. H. Ryu, J. F. Wager (Corvallis, OR, USA) and L. M. Casas (Ft. Monmouth, NJ, USA)	
Characterization of magnetron-sputtered diamond-like thin films for optical coatings in IR	67
G. A. Clarke and R. R. Parsons (Vancouver, B.C., Canada)	
DIAMOND AND RELATED MATERIALS	
<i>Electronic and optical applications of diamond and related materials</i>	
Thermal reaction of Ta thin films with polycrystalline diamond	72
J. S. Chen, E. Kolawa, M.-A. Nicolet and F. S. Pool (Pasadena, CA, USA)	
Effect of oxygen on hydrogenated amorphous carbon films	77
Y. Suefuji, Y. Nakamura, Y. Watanabe, S. Hirayama and K. Tamaki (Kanagawa, Japan)	
Fabrication of amorphous diamond films	82
S. Falabella, D. B. Boercker and D. M. Sanders (Livermore, CA, USA)	

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